



LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.:

4717-12500

APPLICATION NO.:

10/716,901

APPLICANT:

Bruce FAURE

FILING DATE:

November 18, 2003

GROUP:

2812

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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| <i>[Handwritten mark]</i> | AA | 5,374,564 | 12/1994 | Bruel | 437 | 24 | |
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EXAMINER

DATE CONSIDERED

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